

ON Semiconductor®

FDC6304P Digital FET, Dual P-Channel

General Description

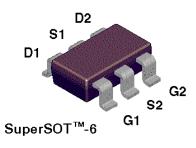
These P-Channel enhancement mode field effect transistor are produced using ON Semiconductor's proprietary, high cell density, DMOS technology. This very high density process is tailored to minimize on-state resistance at low gate drive conditions. This device is designed especially for application in battery power applications—such as notebook computers and cellular phones. This device has excellent on-state resistance even at gate drive voltages as low as 2.5 volts.

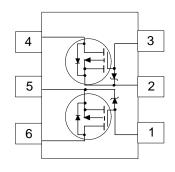
Features

- -25 V, -0.46 A continuous, -1.0 A Peak. $R_{DS(ON)} = 1.5~\Omega~@~V_{GS} = -2.7~V$ $R_{DS(ON)} = 1.1~\Omega~@~V_{GS} = -4.5~V.$
- Very low level gate drive requirements allowing direct operation in 3V circuits. V_{GS(th)} < 1.5 V.
- Gate-Source Zener for ESD ruggedness.
 >6kV Human Body Model.



Mark: .304





Absolute Maximum Ratings $T_A = 25^{\circ}\text{C}$ unless other wise noted

Symbol	Parameter		FDC6304P	Units
V _{DSS}	Drain-Source Voltage		-25	V
V_{GSS}	Gate-Source Voltage		-8	V
I _D	Drain Current - Continuous - Pulsed		-0.46	А
			-1	
P_{D}	Maximum Power Dissipation	(Note 1a)	0.9	W
		(Note 1b)	0.7	
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to 150	℃
ESD	Electrostatic Discharge Rating MIL-STD-883D Human Body Model (100pf / 1500 Ohm)		6.0	kV
THERMA	L CHARACTERISTICS			<u> </u>
$R_{\theta JA}$	Thermal Resistance, Junction-to-Amb	ient (Note 1a)	140	°C/W
R _{eJC}	Thermal Resistance, Junction-to-Case	(Note 1)	60	°C/W

Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \ I_{D} = -250 \mu\text{A}$	-25			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	I_D = -250 μ A, Referenced to 25 °C		-22		mV /°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -20 \text{ V}, \ V_{GS} = 0 \text{ V}$			-1	μA
		$T_J = 55^{\circ}C$			-10	μA
I _{GSS}	Gate - Body Leakage Current	V _{GS} = -8 V, V _{DS} = 0 V			-100	nA
	CTERISTICS (Note 2)					
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	$I_D = -250 \mu\text{A}$, Referenced to 25°C		2.1		mV /°C
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-0.65	-0.86	-1.5	V
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -2.7 \text{ V}, I_D = -0.25 \text{ A}$		1.22	1.5	Ω
		$V_{GS} = -4.5 \text{ V}, I_{D} = -0.5 \text{ A}$		0.87	1.1	
		T _J =125°C		1.21	2	
D(ON)	On-State Drain Current	$V_{GS} = -2.7 \text{ V}, \ V_{DS} = -5 \text{ V}$	-0.5			Α
		$V_{GS} = -4.5 \text{ V}, \ V_{DS} = -5 \text{ V}$	-1			
g _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -0.5 \text{ A}$		0.8		S
DYNAMIC C	HARACTERISTICS					
C _{iss}	Input Capacitance	$V_{DS} = -10 \text{ V}, \ V_{GS} = 0 \text{ V},$ f = 1.0 MHz		62		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		35		pF
C _{rss}	Reverse Transfer Capacitance			9.5		pF
SWITCHING	CHARACTERISTICS (Note 2)		ı	ı	1	
t _{D(on)}	Turn - On Delay Time	$V_{DD} = -6 \text{ V}, I_{D} = -0.5 \text{ A},$		7	20	ns
t _r	Turn - On Rise Time	V_{GS} = -4.5 V, R_{GEN} = 50 Ω		8	20	ns
D(off)	Turn - Off Delay Time			55	110	ns
t _f	Turn - Off Fall Time			35	70	ns
Q _g	Total Gate Charge	$V_{DS} = -5 \text{ V}, I_{D} = -0.25 \text{ A},$ $V_{GS} = -4.5 \text{ V}$		1.1	1.5	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -4.5 V		0.32		nC
Q_{gd}	Gate-Drain Charge			0.28		nC
DRAIN-SOU	RCE DIODE CHARACTERISTICS AND MAX		ı	ı	ı	
l _s	Maximum Continuous Drain-Source Diode For				-0.5	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -0.5 \text{ A} \text{ (Note 2)}$		-0.88	-1.2	V

Notes:

1. R_{gut} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{gut} is guaranteed by design while R_{gut} is determined by the user's board design.



a. 140°C/W on a 0.125 in² pad of 2oz copper.



b. 180°C/W on a 0.005 in² of pad of 2oz copper.

2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%.

Typical Electrical Characteristics

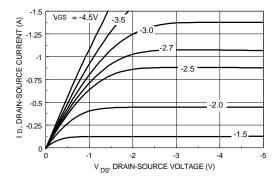


Figure 1. On-Region Characteristics.

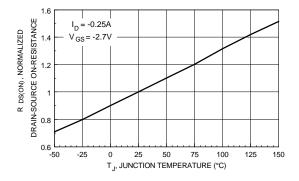


Figure 3. On-Resistance Variation with Temperature.

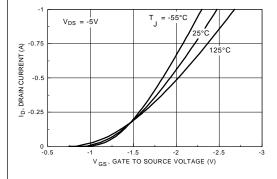


Figure 5. Transfer Characteristics.

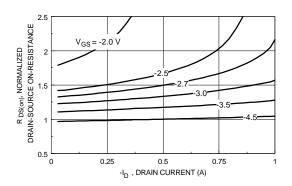


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

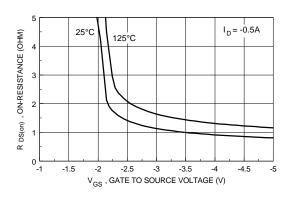


Figure 4. On Resistance Variation with Gate-To- Source Voltage.

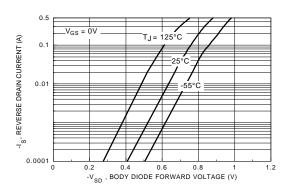


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical And Thermal Characteristics

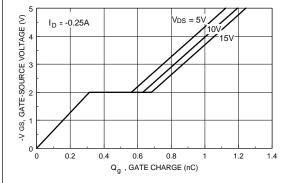


Figure 7. Gate Charge Characteristics.

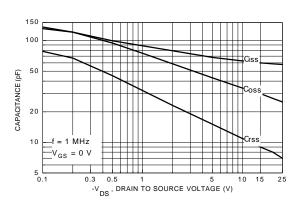


Figure 8. Capacitance Characteristics.

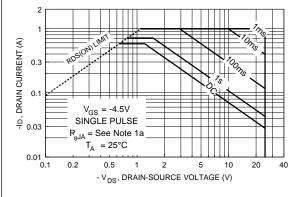


Figure 9. Maximum Safe Operating Area.

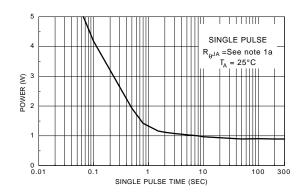


Figure 10. Single Pulse Maximum Power Dissipation.

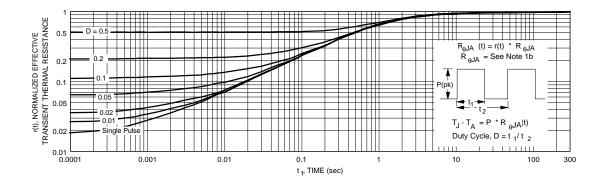


Figure 11. Transient Thermal Response Curve.

Note: Thermal characterization performed using the conditions described in note 1b.Transient thermal response will change depending on the circuit board design.

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